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PATENT
P56138PCT

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In re Application of:

MYOUNG-JIN KIM

Serial No.: 09/582,843

Examiner: AHMED, SAMIR ANWAR

Filed: 5 July 2000

Art Unit: 2623

For: METHOD FOR INSPECTING INFERIORITY IN SHAPE

SECOND SUBMISSION OF INFORMATION DISCLOSURE STATEMENTCommissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. §1.56, and §§1.97 and 1.98 as amended, and in response to the inappropriate Paper No. 14 issued on the 26th of July 2004, Applicant cites, describes, and provides copies of the following art references:

U.S. PATENT REFERENCE:

- U.S. Patent No. 5,339,093 to Kumagai *et al.*, entitled LIQUID CRYSTAL PANEL INSPECTION METHOD, issued on 16 August 1994.

FOREIGN PATENT REFERENCE:

- Canadian Patent No. 2,249,265 to Pearson *et al.*, entitled METHOD, APPARATUS AND SYSTEM FOR VERIFICATION OF PATTERNS, issued on 2 October 1997.
- World Intellectual Property Organization International Patent Publication

WO97/36260 of E.C. Pearson, *et al.* Dated 25 March 1996.

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OTHER DOCUMENTS:

- *Canadian Office Action of the Canadian Patent Application No. 2,317,803 (dated 9 January 2004).*

DISCUSSION

In Paper No. 14, a Communication issued by the Examiner on the 26th of July 2004, the Examiner wrote that:

"The information disclosure statement filed 4/30/04 fails to comply with 37CFR §1.98(a)(2), which requires a legible copy of each U.S. and foreign patent; each publication or that portion which caused it to be listed; and all other information or that portion which caused it to be listed. The first page *only* of the Canadian Patent 2, 249, 265, WO97/36260 Patent and the first page only of the Canadian Office Action of the Canadian Patent Application No. 2,317,803 are provided."

The Examiner's information is incorrect; a copy of postcard receipt confirming the filing of the entirety of all three references, together with the U.S. Patent reference, is enclosed. The fact that the Office is unable to timely handle, without loss or scattering of references filed by the attorneys, has no bearing upon the ability of the Examiner to consider the Information Disclosure Statement; copies are always available through the Scientific Library, and the Examiner is equipped with a telephone suitable for calling the undersigned attorney to advise of the loss of documents internal to the U.S. PTO. The procedure was not followed in this application. Moreover, the Examiner is required to explain to the Supervisory Primary Examiner, inconsistencies within the internal procedures of the U.S. PTO, including the loss or misplacement of references filed. The procedure was not followed, and the assistance of the Supervisory Primary Examiner was not sought.

The examining corp has been advised that the Office has encountered difficulties during the transition to electronic files, and the Commissioner has requested the assistance of the examining corp to address those problems. Should papers be lost in the second filing of the Information Disclosure Statement, the Examiner is therefore, requested to immediately telephone applicant's undersigned attorney in order that the loss may be corrected. The Examiner's cooperation is respectfully solicited as the Office complete its transition from paper files to electronic images, and the undersigned attorney is willing to assist the Examiner and assuring that missing pages or documents are re-submitted.


As noted in the Office Action issued by the Canadian Intellectual Property Office on the 9th of January 2004 in applicant's corresponding Canadian Patent Application No. 2,317,803 corresponding to applicant's above-captioned U.S. Patent Application, Kumagai *et al.* U.S.'093 relates to the present invention which makes it possible for unskilled to inspect the total surface of a liquid crystal panel accurately in short time. "Before the inspection, a unit area of an image without defect is selected from a liquid crystal panel to be inspected. The upper limit reference pattern and the lower limit reference pattern are generated and the brightness of each pixel of the upper limit and the lower limit reference pattern is compared with the brightness of a pattern to be inspected."

Pearson *et al.* CA'265, and Pearson *et al.* WO'260 relates to "a method and apparatus for verifying the establishment of a pattern including means for storing a template of the pattern, means for acquiring an image of the established pattern, a first image processing means to alter at least one of said template and acquired images to produce at least two resulting images, comparison means to compare the two resultant images with each other of said template and acquired images and means to evaluate the results."

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The citation of the foregoing references is not intended to constitute an assertion that other or more relevant art does not exist. Accordingly, the Examiner is requested to make a wide-ranging and thorough search of the relevant art.

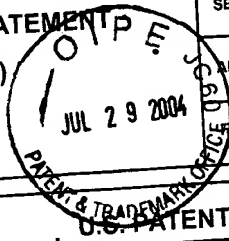
Respectfully submitted,


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INFORMATION DISCLOSURE STATEMENT PTO-1449 (PAGE 1 OF 1)	SERIAL NUMBER 09/582,843	DOCKET NO. P56138PCT
	APPLICANT MYOUNG-JIN KIM FILING DATE 5 July 2000	
GROUP 2623		



U.S. PATENT DOCUMENTS						
EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,339,093	08/94	Kumagai et al.			

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FOREIGN PATENT DOCUMENTS						TRANSLATION	
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
CA 2,249,265	10/97	CANADA			Abstract		
WO 97/36260	03/96	EUROPE			Abstract		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
Canadian Office Action of the Canadian Patent Application No. 2,317,803 (dated 9 January 2004).	

EXAMINER:	DATE CONSIDERED:
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



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30 April 2004

Applicant :MYOUNG-JIN KIM

S.N.: 09/582,843

Filed: 5 July 2000

For: METHOD FOR INSPECTING INFERIORITY IN SHAPE

Document filed:

1. Information Disclosure Statement and PTO-1449 with 3 references
2. Fee transmittal w/ a Check No. 45571 in the amount of \$180.00

